

MOS INTEGRATED CIRCUIT

μ PD4264160, 4265160

64 M-BIT DYNAMIC RAM

4 M-WORD BY 16-BIT, FAST PAGE MODE

Description

The μ PD4264160, 4265160 are 4,194,304 words by 16 bits dynamic CMOS RAMs. The fast page mode capability realize high speed access and low power consumption.

These are packaged in 50-pin plastic TSOP(II).

Features

- 4,194,304 words by 16 bits organization
- Single +3.3 V $\pm$ 0.3 V power supply
- Fast access and cycle time

Part number	Power consumption		Access time (MAX.)	R/W cycle time (MIN.)	Fast page mode cycle time (MIN.)
	Active (MAX.)	Standby(MAX.)			
μ PD4264160-A50	396 mW	1.80 mW (CMOS level input)	50 ns	90 ns	35 ns
μ PD4265160-A50	504 mW				
μ PD4264160-A60	360 mW		60 ns	110 ns	40 ns
μ PD4265160-A60	432 mW				
μ PD4264160-A70	324 mW		70 ns	130 ns	45 ns
μ PD4265160-A70	396 mW				
μ PD4264160-A80	288 mW		80 ns	150 ns	50 ns
μ PD4265160-A80	360 mW				

- $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, $\overline{\text{RAS}}$ only refresh, Hidden refresh

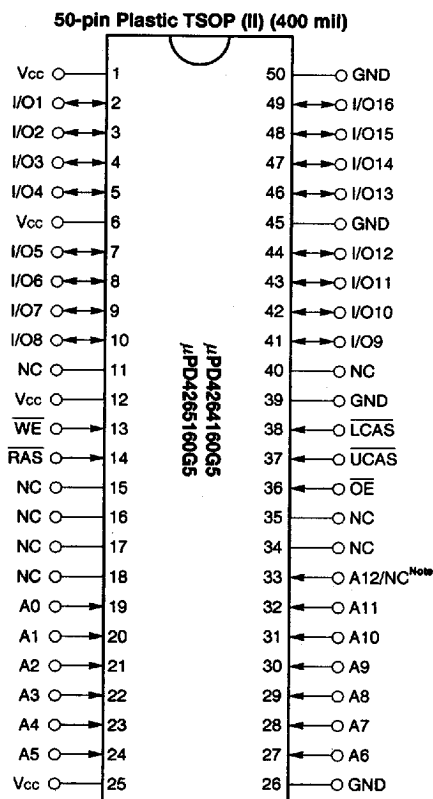
Part number	Row address	Column address	Refresh	Refresh cycle
μ PD4264160	A0 - A12	A0 - A8	$\overline{\text{RAS}}$ only refresh, Normal read/write	8,192 cycles/64 ms
			$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, Hidden refresh	4,096 cycles/64 ms
μ PD4265160	A0 - A11	A0 - A9	$\overline{\text{RAS}}$ only refresh, Normal read/write,	4,096 cycles/64 ms
			$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, Hidden refresh	

The information in this document is subject to change without notice.

Ordering Information

Part number	Access time (MAX.)	Package	Refresh
μPD4264160G5-A50	50 ns	50-pin plastic TSOP (II) (400 mil)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh $\overline{\text{RAS}}$ only refresh Hidden refresh
μPD4264160G5-A60	60 ns		
μPD4264160G5-A70	70 ns		
μPD4264160G5-A80	80 ns		
μPD4265160G5-A50	50 ns		
μPD4265160G5-A60	60 ns		
μPD4265160G5-A70	70 ns		
μPD4265160G5-A80	80 ns		

Pin Configuration (Marking Side)



Note A12 ... μPD4264160
NC ... μPD4265160

A0 to A12 : Address Inputs
I/O1 to I/O16 : Data Inputs/Outputs
RAS : Row Address Strobe
UCAS : Upper Byte Column Address Strobe
LCAS : Lower Byte Column Address Strobe
WE : Write Enable
OE : Output Enable
Vcc : Power Supply
GND : Ground
NC : No Connection

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Input/Output Pin Functions

The μPD4264160, 4265160 have input pins $\overline{RAS}$, $\overline{UCAS}$, $\overline{LCAS}$, $\overline{WE}$, $\overline{OE}$, Address^{Note} and input/output pins I/O1 to I/O16.

Pin name	Input/Output	Function
$\overline{RAS}$ (Row address strobe)	Input	$\overline{RAS}$ activates the sense amplifier by latching a row address and selecting a corresponding word line. It refreshes memory cell array of one line selected by the row address. It also selects the following function. • $\overline{CAS}$ before $\overline{RAS}$ refresh
$\overline{UCAS}$, $\overline{LCAS}$ (Upper, Lower column address strobe)	Input	$\overline{UCAS}$, $\overline{LCAS}$ activates data input/output circuit by latching column address and selecting a digit line connected with the sense amplifier.
A0 to A _x ^{Note} (Address inputs)	Input	Address bus. Input total 22-bit of address signal, upper bits and lower bits ^{Note} in sequence (address multiplex method). Therefore, one word is selected from 4,194,304-word by 16-bit memory cell array. In actual operation, latch row address by specifying row address and activating $\overline{RAS}$. Then, switch the address bus to column address and activate $\overline{CAS}$. Each address is taken into the device when $\overline{RAS}$ and $\overline{CAS}$ are activated. Therefore, the address input setup time (t_{ASR} , t_{ASC}) and hold time (t_{RAH} , t_{CAH}) are specified for the activation of $\overline{RAS}$ and $\overline{CAS}$.
$\overline{WE}$ (Write enable)	Input	Write control signal. Write operation is executed by activating $\overline{RAS}$, $\overline{CAS}$ and $\overline{WE}$.
$\overline{OE}$ (Output enable)	Input	Read control signal. Read operation can be executed by activating $\overline{RAS}$, $\overline{CAS}$ and $\overline{OE}$. If $\overline{WE}$ is activated during read operation, $\overline{OE}$ is to be ineffective in the device. Therefore, read operation cannot be executed.
I/O1 to I/O16 (Data inputs/outputs)	Input/Output	16-bit data bus. I/O1 to I/O16 are used to input/output data.

Note

Part number	Address inputs	Upper bits	Lower bits
μPD4264160	A0-A12	13	9
μPD4265160	A0-A11	12	10

Electrical Specifications (Preliminary)

- $\overline{\text{CAS}}$ means $\overline{\text{UCAS}}$ and $\overline{\text{LCAS}}$.
- All voltages are referenced to GND.
- After power up ($V_{CC} \geq V_{CC(MIN.)}$), wait more than 100 μs ($\overline{\text{RAS}}$, $\overline{\text{CAS}}$ inactive) and then, execute eight $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ or $\overline{\text{RAS}}$ only refresh cycles as dummy cycles to initialize internal circuit.

Absolute Maximum Ratings

Parameter	Symbol	Condition	Rating	Unit
Voltage on any pin relative to GND	V_T		-0.5 to +4.6	V
Supply voltage	V_{CC}		-0.5 to +4.6	V
Output current	I_O		20	mA
Power dissipation	P_D		1	W
Operating ambient temperature	T_A		0 to +70	$^{\circ}\text{C}$
Storage temperature	T_{stg}		-55 to +125	$^{\circ}\text{C}$

Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Supply voltage	V_{CC}		3.0	3.3	3.6	V
High level input voltage	V_{IH}		2.0		$V_{CC} + 0.3$	V
Low level input voltage	V_{IL}		-0.3		+0.8	V
Operating ambient temperature	T_A		0		70	$^{\circ}\text{C}$

Capacitance ($T_A = 25^{\circ}\text{C}$, $f = 1\text{ MHz}$)

Parameter	Symbol	Test condition	MIN.	TYP.	MAX.	Unit
Input capacitance	C_{I1}	Address			5	pF
	C_{I2}	$\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$, $\overline{\text{OE}}$			7	
Data input/output capacitance	$C_{I/O}$	I/O			7	pF

DC Characteristics (Recommended operating conditions unless otherwise noted)

[μPD4264160]

Parameter	Symbol	Test condition	MIN.	MAX.	Unit	Notes
Operating current	I _{CC1}	$\overline{\text{RAS}}, \overline{\text{CAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	110	mA	1, 2, 3
			$t_{\text{RAC}} = 60 \text{ ns}$	100		
			$t_{\text{RAC}} = 70 \text{ ns}$	90		
			$t_{\text{RAC}} = 80 \text{ ns}$	80		
Standby current	I _{CC2}	$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.}), I_o = 0 \text{ mA}$		1.0	mA	
		$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{CC}} - 0.2 \text{ V}, I_o = 0 \text{ mA}$		0.5		
$\overline{\text{RAS}}$ only refresh current	I _{CC3}	$\overline{\text{RAS}}$ Cycling, $\overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.})$ $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	110	mA	1, 2, 3, 4
			$t_{\text{RAC}} = 60 \text{ ns}$	100		
			$t_{\text{RAC}} = 70 \text{ ns}$	90		
			$t_{\text{RAC}} = 80 \text{ ns}$	80		
Operating current (Fast page mode)	I _{CC4}	$\overline{\text{RAS}} \leq V_{\text{IL}}(\text{MAX.}), \overline{\text{CAS}}$ Cycling $t_{\text{PC}} = t_{\text{PC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	90	mA	1, 2, 5
			$t_{\text{RAC}} = 60 \text{ ns}$	80		
			$t_{\text{RAC}} = 70 \text{ ns}$	70		
			$t_{\text{RAC}} = 80 \text{ ns}$	60		
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh current	I _{CC5}	$\overline{\text{RAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	140	mA	1, 2
			$t_{\text{RAC}} = 60 \text{ ns}$	120		
			$t_{\text{RAC}} = 70 \text{ ns}$	110		
			$t_{\text{RAC}} = 80 \text{ ns}$	100		
Input leakage current	I _{I(L)}	$V_i = 0 \text{ to } 3.6 \text{ V}$ All other pins not under test = 0 V	-5	+5	μA	
Output leakage current	I _{O(L)}	$V_o = 0 \text{ to } 3.6 \text{ V}$ Output is disabled (Hi-Z)	-5	+5	μA	
High level output voltage	V _{OH}	$I_o = -2.0 \text{ mA}$	2.4		V	
Low level output voltage	V _{OL}	$I_o = +2.0 \text{ mA}$		0.4	V	

[μPD4265160]

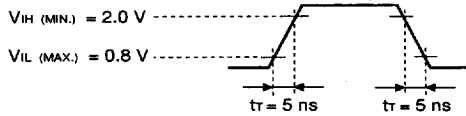
Parameter	Symbol	Test condition	MIN.	MAX.	Unit	Notes
Operating current	I _{CC1}	$\overline{\text{RAS}}, \overline{\text{CAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	140	mA	1, 2, 3
			$t_{\text{RAC}} = 60 \text{ ns}$	120		
			$t_{\text{RAC}} = 70 \text{ ns}$	110		
			$t_{\text{RAC}} = 80 \text{ ns}$	100		
Standby current	I _{CC2}	$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.}), I_o = 0 \text{ mA}$		1.0	mA	
		$\overline{\text{RAS}}, \overline{\text{CAS}} \geq V_{\text{CC}} - 0.2 \text{ V}, I_o = 0 \text{ mA}$		0.5		
RAS only refresh current	I _{CC3}	$\overline{\text{RAS}}$ Cycling, $\overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.})$ $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	140	mA	1, 2, 3, 4
			$t_{\text{RAC}} = 60 \text{ ns}$	120		
			$t_{\text{RAC}} = 70 \text{ ns}$	110		
			$t_{\text{RAC}} = 80 \text{ ns}$	100		
Operating current (Fast page mode)	I _{CC4}	$\overline{\text{RAS}} \leq V_{\text{IL}}(\text{MAX.}), \overline{\text{CAS}}$ Cycling $t_{\text{PC}} = t_{\text{PC}}(\text{MIN.}), I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	90	mA	1, 2, 5
			$t_{\text{RAC}} = 60 \text{ ns}$	80		
			$t_{\text{RAC}} = 70 \text{ ns}$	70		
			$t_{\text{RAC}} = 80 \text{ ns}$	60		
CAS before RAS refresh current	I _{CC5}	$\overline{\text{RAS}}$ Cycling $t_{\text{RC}} = t_{\text{RC}}(\text{MIN.})$ $I_o = 0 \text{ mA}$	$t_{\text{RAC}} = 50 \text{ ns}$	140	mA	1, 2
			$t_{\text{RAC}} = 60 \text{ ns}$	120		
			$t_{\text{RAC}} = 70 \text{ ns}$	110		
			$t_{\text{RAC}} = 80 \text{ ns}$	100		
Input leakage current	I _{I(L)}	$V_i = 0 \text{ to } 3.6 \text{ V}$ All other pins not under test = 0 V	-5	+5	μA	
Output leakage current	I _{O(L)}	$V_o = 0 \text{ to } 3.6 \text{ V}$ Output is disabled (Hi-Z)	-5	+5	μA	
High level output voltage	V _{OH}	$I_o = -2.0 \text{ mA}$	2.4		V	
Low level output voltage	V _{OL}	$I_o = +2.0 \text{ mA}$		0.4	V	

- Notes**
1. I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rates (t_{RC} and t_{PC}).
 2. Specified values are obtained with outputs unloaded.
 3. I_{CC1} and I_{CC3} are measured assuming that address can be changed once or less during $\overline{\text{RAS}} \leq V_{\text{IL}}(\text{MAX.})$ and $\overline{\text{CAS}} \geq V_{\text{IH}}(\text{MIN.})$.
 4. I_{CC3} is measured assuming that all column address inputs are held at either high or low.
 5. I_{CC4} is measured assuming that all column address inputs are switched only once during each fast page cycle.

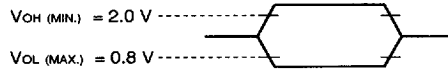
AC Characteristics (Recommended Operating Conditions unless otherwise noted)

AC Characteristics Test Conditions

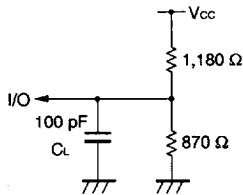
(1) Input timing specification



(2) Output timing specification



(3) Output load condition



Common to Read, Write, Read Modify Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read / Write cycle time	t _{RC}	90	—	110	—	130	—	150	—	ns	
RAS precharge time	t _{RP}	30	—	40	—	50	—	60	—	ns	
CAS precharge time	t _{CPN}	8	—	10	—	10	—	10	—	ns	
RAS pulse width	t _{RAS}	50	10,000	60	10,000	70	10,000	80	10,000	ns	
CAS pulse width	t _{CAS}	13	10,000	15	10,000	18	10,000	20	10,000	ns	
RAS hold time	t _{RSH}	13	—	15	—	18	—	20	—	ns	
CAS hold time	t _{CASH}	50	—	60	—	70	—	80	—	ns	
RAS to CAS delay time	t _{RCD}	18	37	20	45	20	52	25	60	ns	1
RAS to column address delay time	t _{RAD}	13	25	15	30	15	35	17	40	ns	1
CAS to RAS precharge time	t _{CRP}	5	—	5	—	5	—	5	—	ns	2
Row address setup time	t _{ASR}	0	—	0	—	0	—	0	—	ns	
Row address hold time	t _{RAH}	8	—	10	—	10	—	12	—	ns	
Column address setup time	t _{ASC}	0	—	0	—	0	—	0	—	ns	
Column address hold time	t _{CAH}	13	—	15	—	15	—	15	—	ns	
OE lead time referenced to RAS	t _{OES}	0	—	0	—	0	—	0	—	ns	
CAS to data setup time	t _{CLZ}	0	—	0	—	0	—	0	—	ns	
OE to data setup time	t _{OLZ}	0	—	0	—	0	—	0	—	ns	
OE to data delay time	t _{OED}	10	—	13	—	15	—	15	—	ns	
Masked byte write hold time referenced to RAS	t _{MRH}	0	—	0	—	0	—	0	—	ns	
Transition time (rise and fall)	t _r	3	50	3	50	3	50	3	50	ns	
Refresh time	t _{REF}	—	64	—	64	—	64	—	64	ms	

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Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{\text{RAS}}$
$\text{trAD} \leq \text{trAD (MAX.)}$ and $\text{trCD} \leq \text{trCD (MAX.)}$	trAC (MAX.)	trAC (MAX.)
$\text{trAD} > \text{trAD (MAX.)}$ and $\text{trCD} \leq \text{trCD (MAX.)}$	tAA (MAX.)	$\text{trAD} + \text{tAA (MAX.)}$
$\text{trCD} > \text{trCD (MAX.)}$	tCAC (MAX.)	$\text{trCD} + \text{tCAC (MAX.)}$

trAD (MAX.) and trCD (MAX.) are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (trAC , tAA or tCAC) is to be used for finding out when output data will be available. Therefore, the input conditions $\text{trAD} \geq \text{trAD (MAX.)}$ and $\text{trCD} \geq \text{trCD (MAX.)}$ will not cause any operation problems.

2. tCRP (MIN.) requirement is applied to $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ cycles.

Read Cycle

Parameter	Symbol	$\text{trAC} = 50 \text{ ns}$		$\text{trAC} = 60 \text{ ns}$		$\text{trAC} = 70 \text{ ns}$		$\text{trAC} = 80 \text{ ns}$		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Access time from $\overline{\text{RAS}}$	trAC	—	50	—	60	—	70	—	80	ns	1
Access time from $\overline{\text{CAS}}$	tCAC	—	13	—	15	—	18	—	20	ns	1
Access time from column address	tAA	—	25	—	30	—	35	—	40	ns	1
Access time from $\overline{\text{OE}}$	tOEA	—	13	—	15	—	18	—	20	ns	
Column address lead time referenced to $\overline{\text{RAS}}$	trAL	25	—	30	—	35	—	40	—	ns	
Read command setup time	trCS	0	—	0	—	0	—	0	—	ns	
Read command hold time referenced to $\overline{\text{RAS}}$	trRH	0	—	0	—	0	—	0	—	ns	2
Read command hold time referenced to $\overline{\text{CAS}}$	trCH	0	—	0	—	0	—	0	—	ns	2
Output buffer turn-off delay time from $\overline{\text{OE}}$	tOEZ	0	10	0	13	0	15	0	15	ns	3
Output buffer turn-off delay time from $\overline{\text{CAS}}$	tOFF	0	10	0	13	0	15	0	15	ns	3

Notes 1. For read cycles, access time is defined as follows:

Input conditions	Access time	Access time from $\overline{\text{RAS}}$
$\text{trAD} \leq \text{trAD (MAX.)}$ and $\text{trCD} \leq \text{trCD (MAX.)}$	trAC (MAX.)	trAC (MAX.)
$\text{trAD} > \text{trAD (MAX.)}$ and $\text{trCD} \leq \text{trCD (MAX.)}$	tAA (MAX.)	$\text{trAD} + \text{tAA (MAX.)}$
$\text{trCD} > \text{trCD (MAX.)}$	tCAC (MAX.)	$\text{trCD} + \text{tCAC (MAX.)}$

trAD (MAX.) and trCD (MAX.) are specified as reference points only; they are not restrictive operating parameters. They are used to determine which access time (trAC , tAA or tCAC) is to be used for finding out when output data will be available. Therefore, the input conditions $\text{trAD} \geq \text{trAD (MAX.)}$ and $\text{trCD} \geq \text{trCD (MAX.)}$ will not cause any operation problems.

2. Either trCH (MIN.) or trRH (MIN.) should be met in read cycles.
3. tOFF (MAX.) and tOEZ (MAX.) define the time when the output achieves the condition of Hi-Z and is not referenced to VOH or VOL .

Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Notes
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$\overline{WE}$ hold time referenced to $\overline{CAS}$	twch	8	—	10	—	10	—	15	—	ns	1
$\overline{WE}$ pulse width	twp	8	—	10	—	10	—	15	—	ns	1
$\overline{WE}$ lead time referenced to $\overline{RAS}$	trwl	13	—	15	—	15	—	15	—	ns	
$\overline{WE}$ lead time referenced to $\overline{CAS}$	tcwl	13	—	15	—	15	—	15	—	ns	
$\overline{WE}$ setup time	twcs	0	—	0	—	0	—	0	—	ns	2
$\overline{OE}$ hold time	toeh	0	—	0	—	0	—	0	—	ns	
Data-in setup time	t _{DS}	0	—	0	—	0	—	0	—	ns	3
Data-in hold time	t _{DH}	10	—	10	—	15	—	15	—	ns	3

- Notes**
1. t_{WP} (MIN.) is applied to late write cycles or read modify write cycles. In early write cycles, twch (MIN.) should be met.
 2. If twcs ≥ twcs (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle.
 3. t_{DS} (MIN.) and t_{DH} (MIN.) are referenced to the $\overline{CAS}$ falling edge in early write cycles. In late write cycles and read modify write cycles, they are referenced to the $\overline{WE}$ falling edge.

Read Modify Write Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Read modify write cycle time	trwc	128	—	153	—	175	—	195	—	ns	
$\overline{RAS}$ to $\overline{WE}$ delay time	trwd	70	—	83	—	95	—	105	—	ns	1
$\overline{CAS}$ to $\overline{WE}$ delay time	tcwd	33	—	38	—	43	—	45	—	ns	1
Column address to $\overline{WE}$ delay time	tawd	45	—	53	—	60	—	65	—	ns	1

- Note**
1. If twcs ≥ twcs (MIN.), the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If trwd ≥ trwd (MIN.), tcwd ≥ tcwd (MIN.), tawd ≥ tawd (MIN.) and tcpwd ≥ tcpwd (MIN.), the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

Fast Page Mode

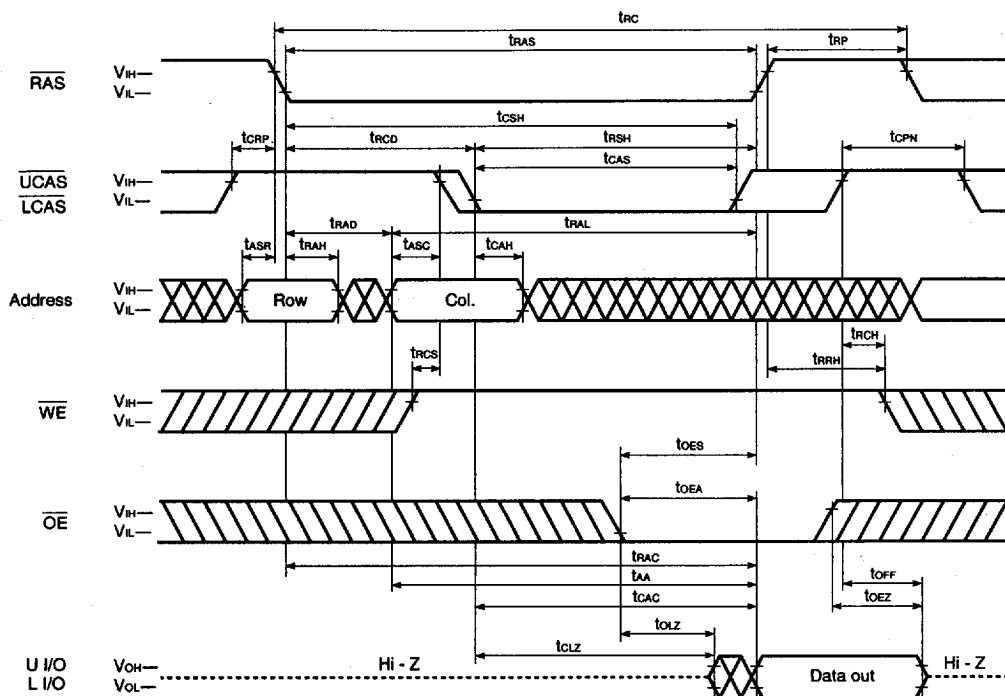
Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Fast page mode cycle time	t _{PC}	35	—	40	—	45	—	50	—	ns	
Access time from $\overline{\text{CAS}}$ precharge	t _{ACP}	—	30	—	35	—	40	—	45	ns	
$\overline{\text{RAS}}$ pulse width	t _{RASP}	50	125,000	60	125,000	70	125,000	80	125,000	ns	
$\overline{\text{CAS}}$ precharge time	t _{CP}	8	—	10	—	10	—	10	—	ns	
$\overline{\text{RAS}}$ hold time from $\overline{\text{CAS}}$ precharge	t _{RHCP}	30	—	35	—	40	—	45	—	ns	
Read modify write cycle time	t _{PRWC}	73	—	83	—	90	—	95	—	ns	
$\overline{\text{CAS}}$ precharge to $\overline{\text{WE}}$ delay time	t _{CPWD}	50	—	58	—	65	—	70	—	ns	1

Note 1. If $t_{\text{WCS}} \geq t_{\text{WCS}}(\text{MIN.})$, the cycle is an early write cycle and the data out will remain Hi-Z through the entire cycle. If $t_{\text{RWD}} \geq t_{\text{RWD}}(\text{MIN.})$, $t_{\text{CWD}} \geq t_{\text{CWD}}(\text{MIN.})$, $t_{\text{AWD}} \geq t_{\text{AWD}}(\text{MIN.})$ and $t_{\text{CPWD}} \geq t_{\text{CPWD}}(\text{MIN.})$, the cycle is a read modify write cycle and the data out will contain data read from the selected cell. If neither of the above conditions is met, the state of the data out is indeterminate.

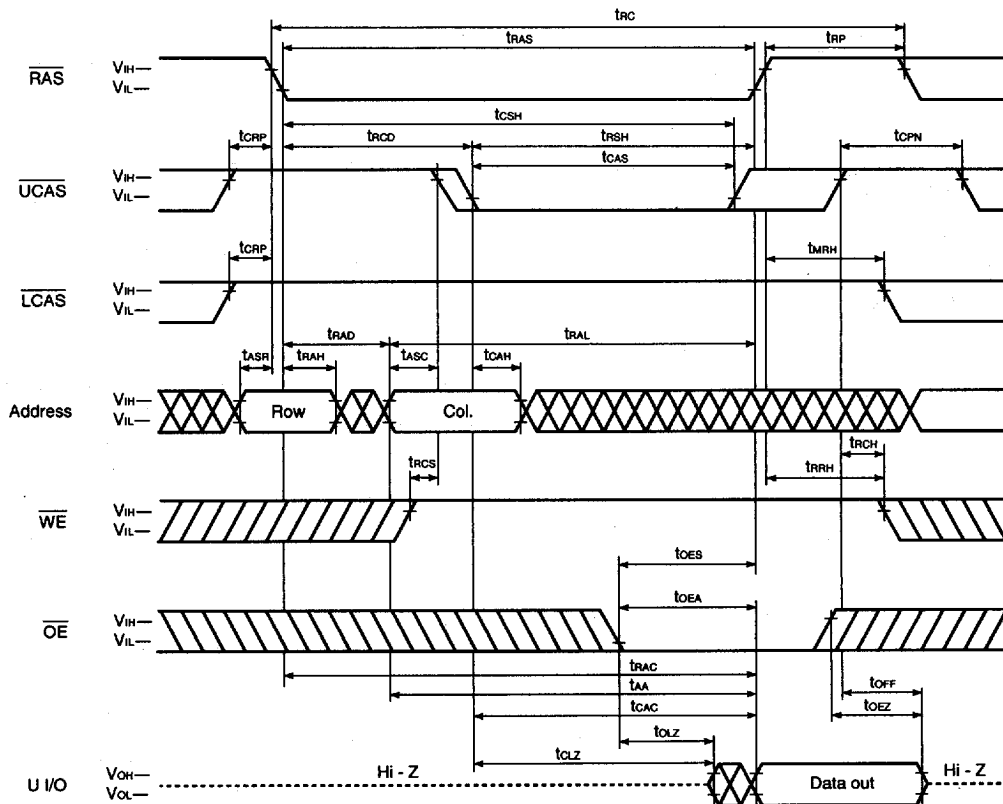
Refresh Cycle

Parameter	Symbol	t _{RAC} = 50 ns		t _{RAC} = 60 ns		t _{RAC} = 70 ns		t _{RAC} = 80 ns		Unit	Note
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
$\overline{\text{CAS}}$ setup time	t _{CSR}	5	—	5	—	5	—	5	—	ns	
$\overline{\text{CAS}}$ hold time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh)	t _{CHR}	10	—	10	—	10	—	10	—	ns	
$\overline{\text{RAS}}$ precharge $\overline{\text{CAS}}$ hold time	t _{RPC}	5	—	5	—	5	—	5	—	ns	
$\overline{\text{WE}}$ setup time	t _{WSR}	10	—	10	—	10	—	10	—	ns	
$\overline{\text{WE}}$ hold time	t _{WHR}	15	—	15	—	15	—	15	—	ns	

Read Cycle

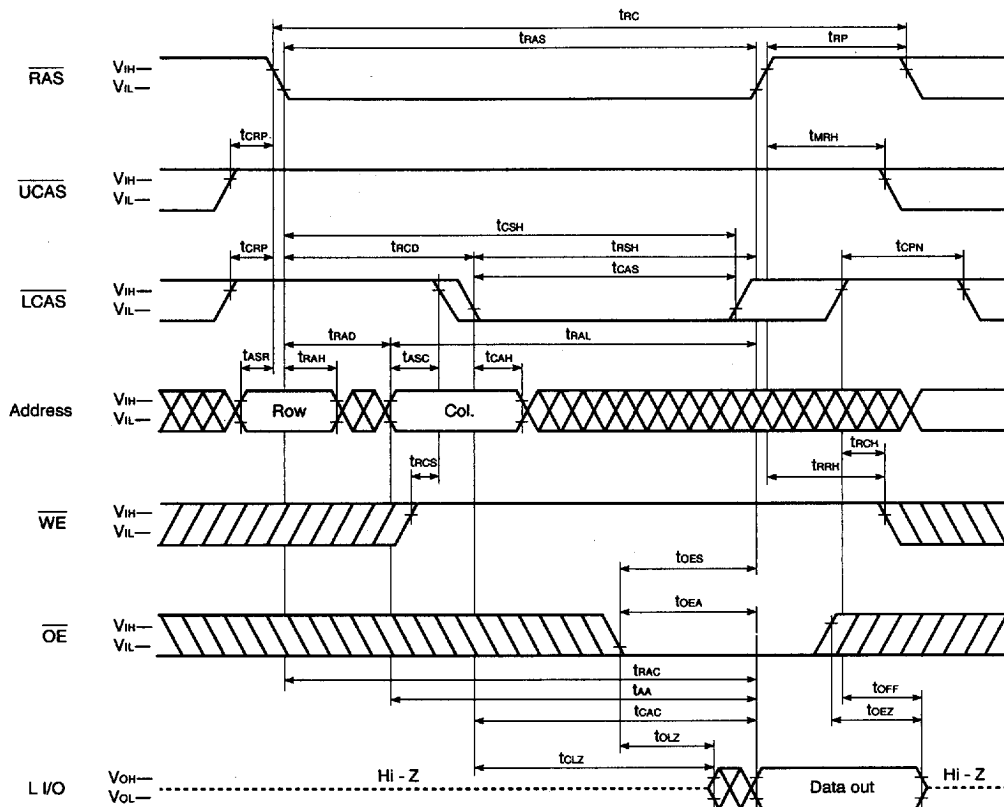


Upper Byte Read Cycle



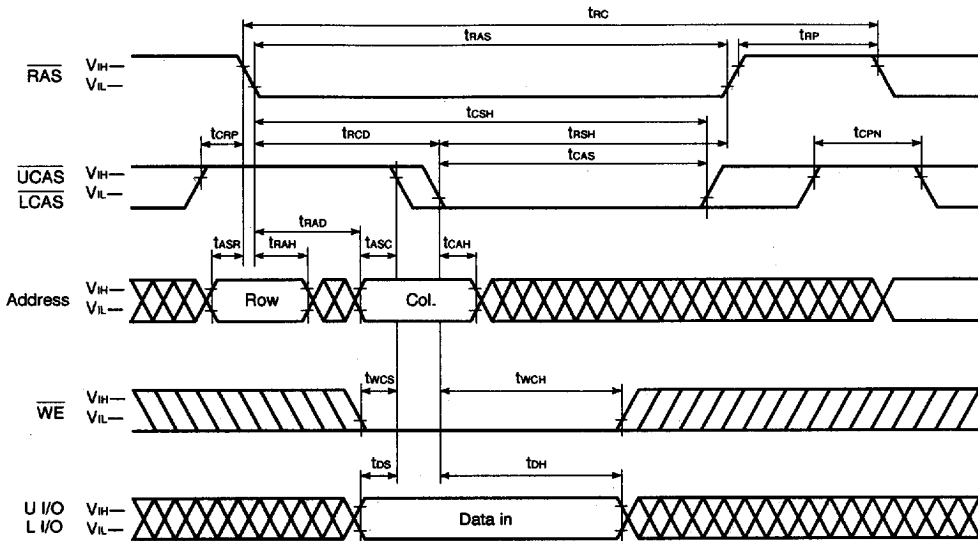
Remark L I/O: Hi-Z

Lower Byte Read Cycle



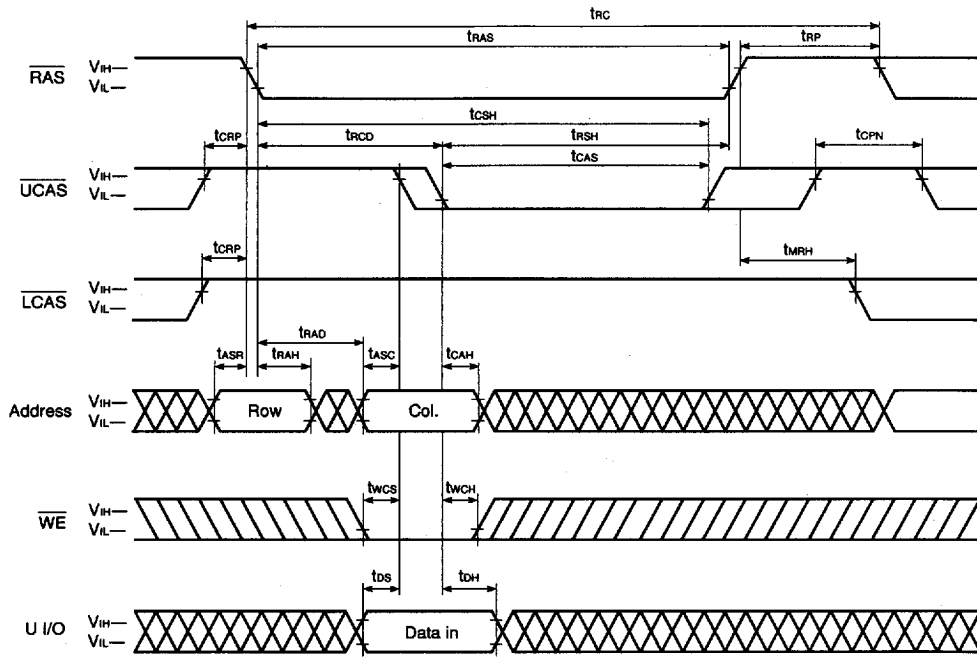
Remark U I/O: Hi-Z

Early Write Cycle



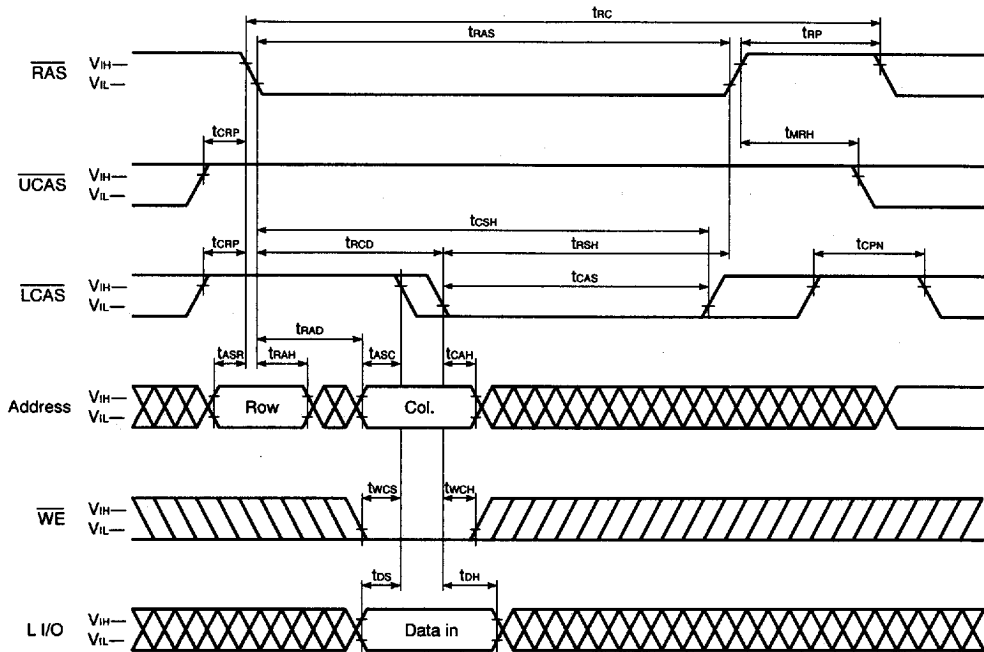
Remark $\overline{OE}$: Don't care

Upper Byte Early Write Cycle



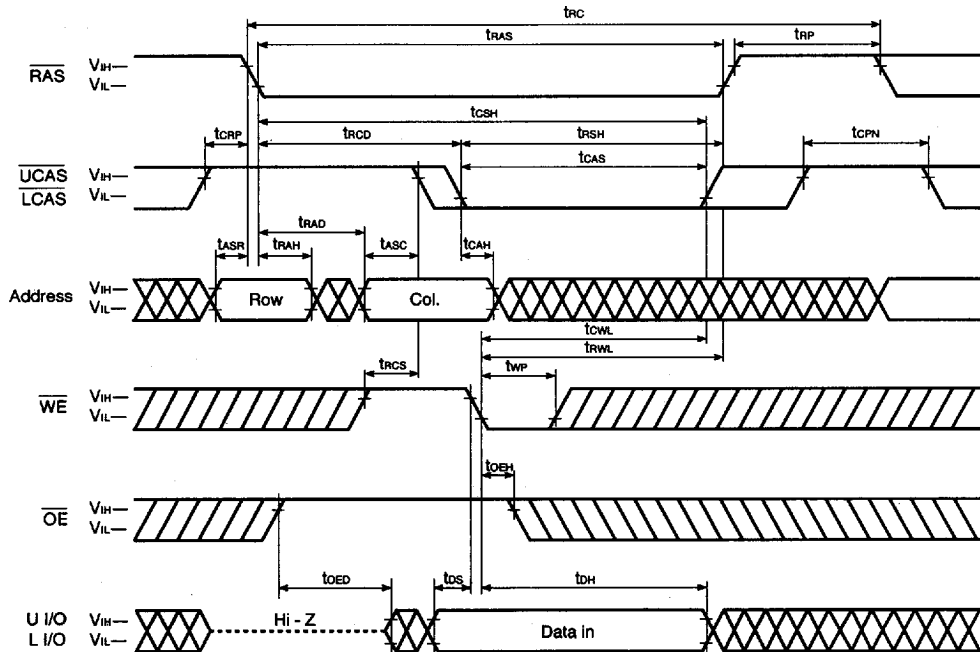
Remark $\overline{\text{OE}}$, L I/O: Don't care

Lower Byte Early Write Cycle

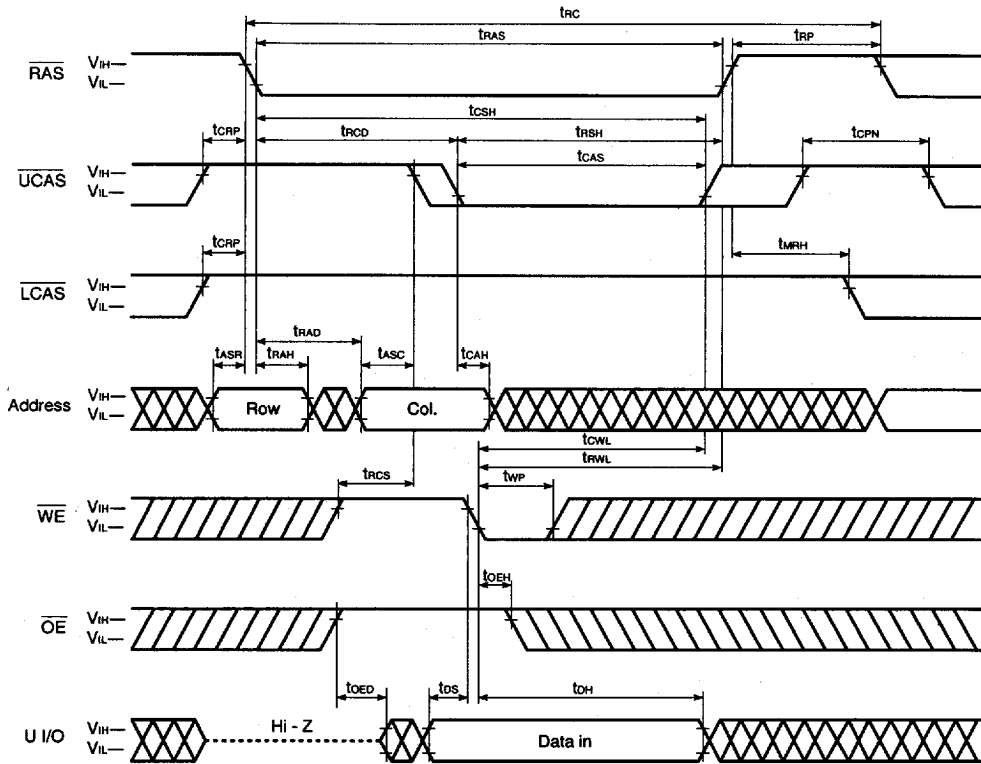


Remark $\overline{OE}$, U I/O: Don't care

Late Write Cycle

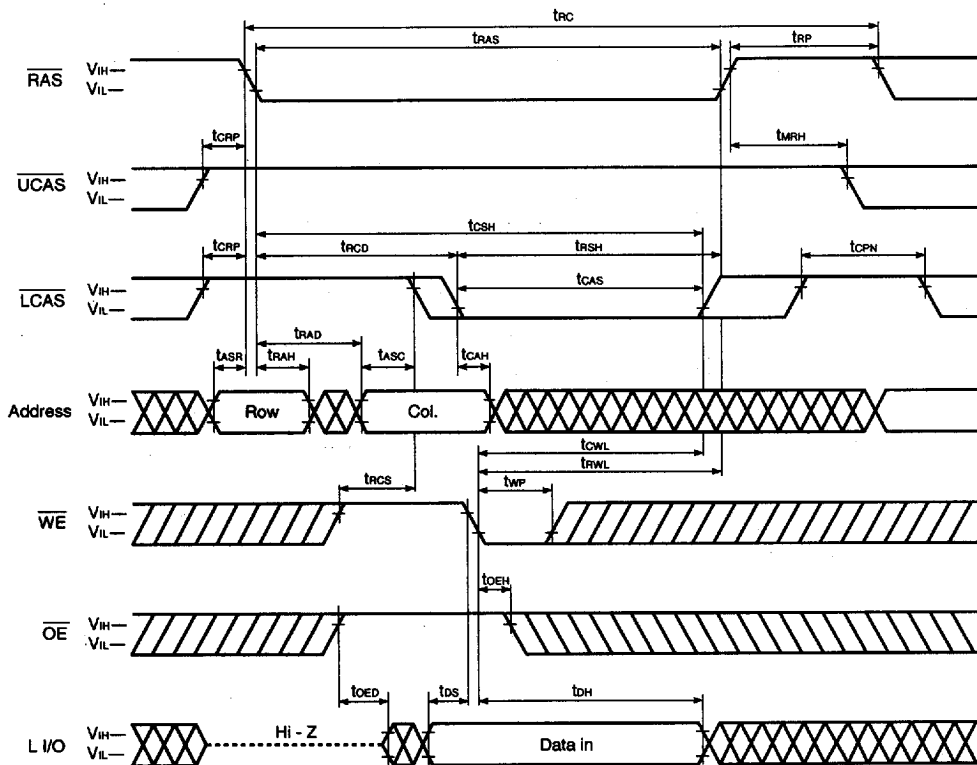


Upper Byte Late Write Cycle



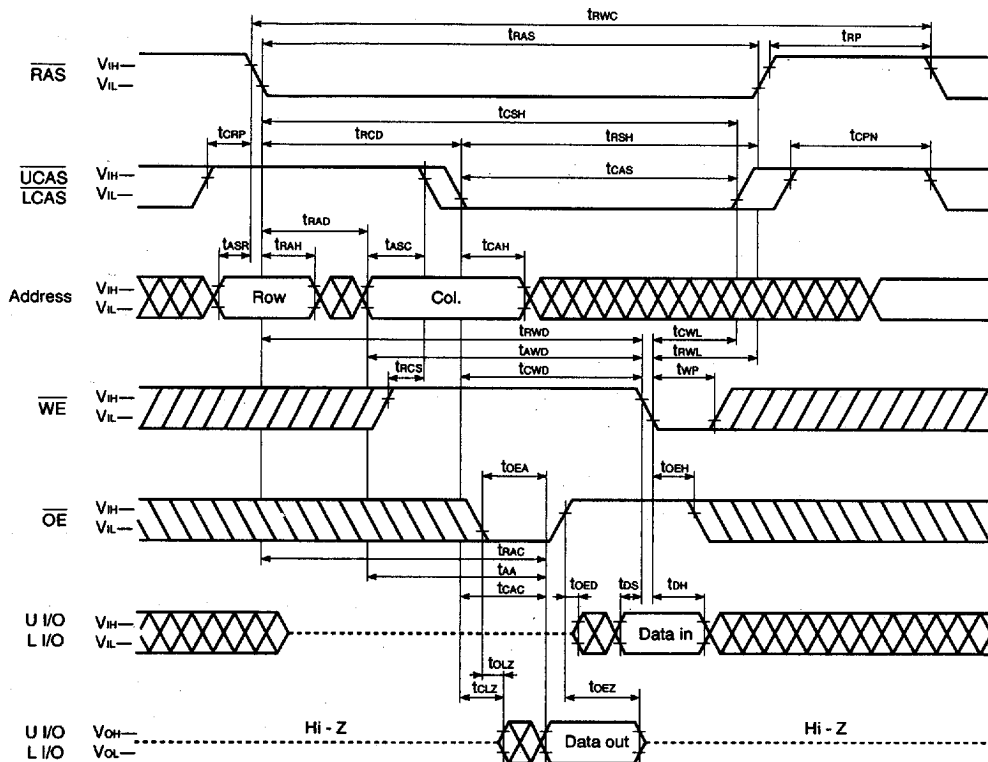
Remark L I/O: Don't care

Lower Byte Late Write Cycle



Remark U I/O: Don't care

Read Modify Write Cycle



[illegible]

656

6427525 0091467 881

The timing diagram illustrates the relationship between various control and data signals for the 64K1602 LCD module. The signals and their timing parameters are as follows:

- RAS**: Row Address Strobe. Timing parameters: t_{rWC} (RAS to WE), t_{rP} (RAS to OE), t_{CRP} (RAS to UCAS), t_{MRH} (RAS to WE).
- UCAS**: User Command Address Strobe. Timing parameters: t_{CRP} (RAS to UCAS), t_{MRH} (RAS to WE).
- LCAS**: LCD Command Address Strobe. Timing parameters: t_{CRP} (RAS to LCAS), t_{RCD} (RAS to WE), t_{CSH} (RAS to WE), t_{RSH} (RAS to WE), t_{CAS} (RAS to WE), t_{CPN} (RAS to WE).
- Address**: Row and Column addresses. Timing parameters: t_{RAD} (RAS to WE), t_{ASR} (RAS to WE), t_{RAH} (RAS to WE), t_{ASC} (RAS to WE), t_{CAH} (RAS to WE).
- WE**: Write Enable. Timing parameters: t_{RWD} (RAS to WE), t_{AWD} (RAS to WE), t_{CWD} (RAS to WE), t_{CWL} (RAS to WE), t_{RWL} (RAS to WE), t_{WP} (RAS to WE).
- OE**: Output Enable. Timing parameters: t_{OEA} (RAS to OE), t_{OEH} (RAS to OE), t_{RAC} (RAS to OE), t_{AA} (RAS to OE), t_{CAC} (RAS to OE).
- L I/O**: LCD Data In/Out. Timing parameters: t_{OED} (RAS to OE), t_{DS} (RAS to OE), t_{DH} (RAS to OE), t_{OLZ} (RAS to OE), t_{OLZ} (RAS to OE), t_{OEZ} (RAS to OE).
- I/O**: Data In/Out. Timing parameters: t_{OLZ} (RAS to OE), t_{OLZ} (RAS to OE), t_{OEZ} (RAS to OE).

Remark In this cycle, the input data to Upper I/O is ineffective. The data out of that remains Hi-Z.

6427525 0091469 654

The diagram illustrates the timing relationships between the 68000 microprocessor's control signals and its internal operations. The signals shown are:

- RAS**: Row Address Strobe
- UCAS**: Upper Chip Address Strobe
- LCAS**: Lower Chip Address Strobe
- Address**: Data bus address (Row and Column)
- WE**: Write Enable
- OE**: Output Enable
- U I/O**: User Input/Output signal
- L I/O**: Local Input/Output signal

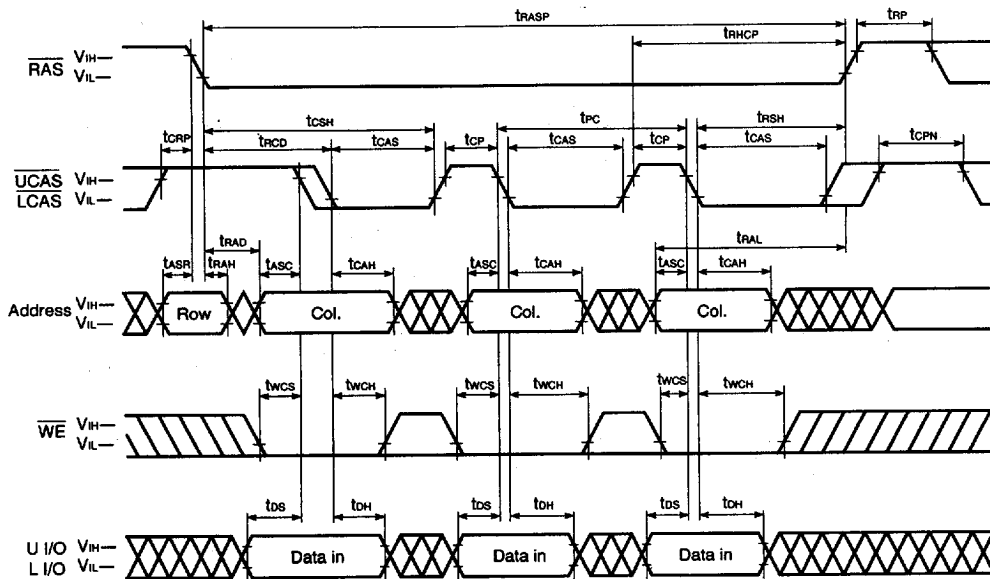
Key timing parameters labeled include:

- t_{RASP} , t_{RHCP} , t_{RP}
- t_{CSPH} , t_{PCD} , t_{CAS} , t_{PC} , t_{RSH} , t_{CPN}
- t_{ORP} , t_{TRP} , t_{CAH} , t_{TCH} , t_{RRH}
- t_{RAD} , t_{RAH} , t_{ASC} , t_{CAH} , t_{ASC} , t_{CAH} , t_{ASC} , t_{CAH} , t_{ASC} , t_{CAH}
- t_{RCS} , t_{RCH} , t_{TOES} , t_{OEA} , t_{OLZ} , t_{ACP} , t_{TOEZ} , t_{AA} , t_{CAC} , t_{OFF} , t_{TCLZ}

The diagram shows the sequence of events for reading and writing data, highlighting the critical paths and setup/hold times required for reliable operation.

- Remarks**
1. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive $\overline{\text{CAS}}$ cycles within the same $\overline{\text{RAS}}$ cycle.
 2. This cycle can be used to control either $\overline{\text{UCAS}}$ or $\overline{\text{LCAS}}$ only. Or, it can be used to control $\overline{\text{UCAS}}$ or $\overline{\text{LCAS}}$ simultaneously, or at random.

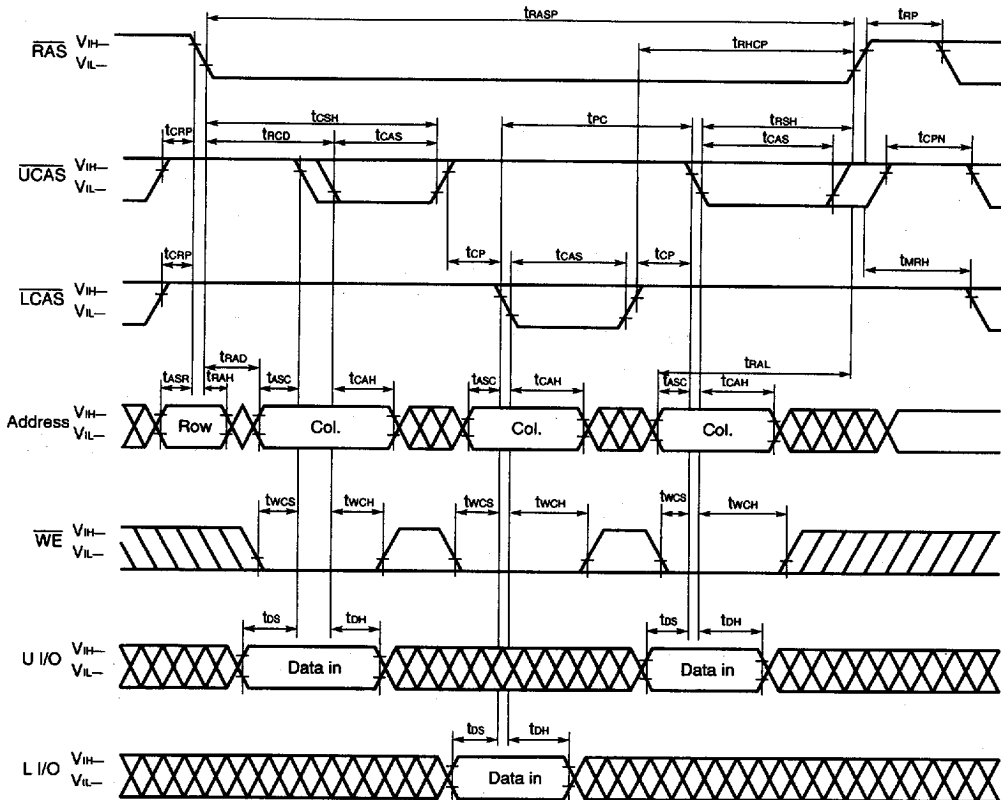
Fast Page Mode Early Write Cycle



Remarks 1. $\overline{\text{OE}}$: Don't care

2. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive $\overline{\text{CAS}}$ cycles within the same $\overline{\text{RAS}}$ cycle.

Fast Page Mode Byte Early Write Cycle



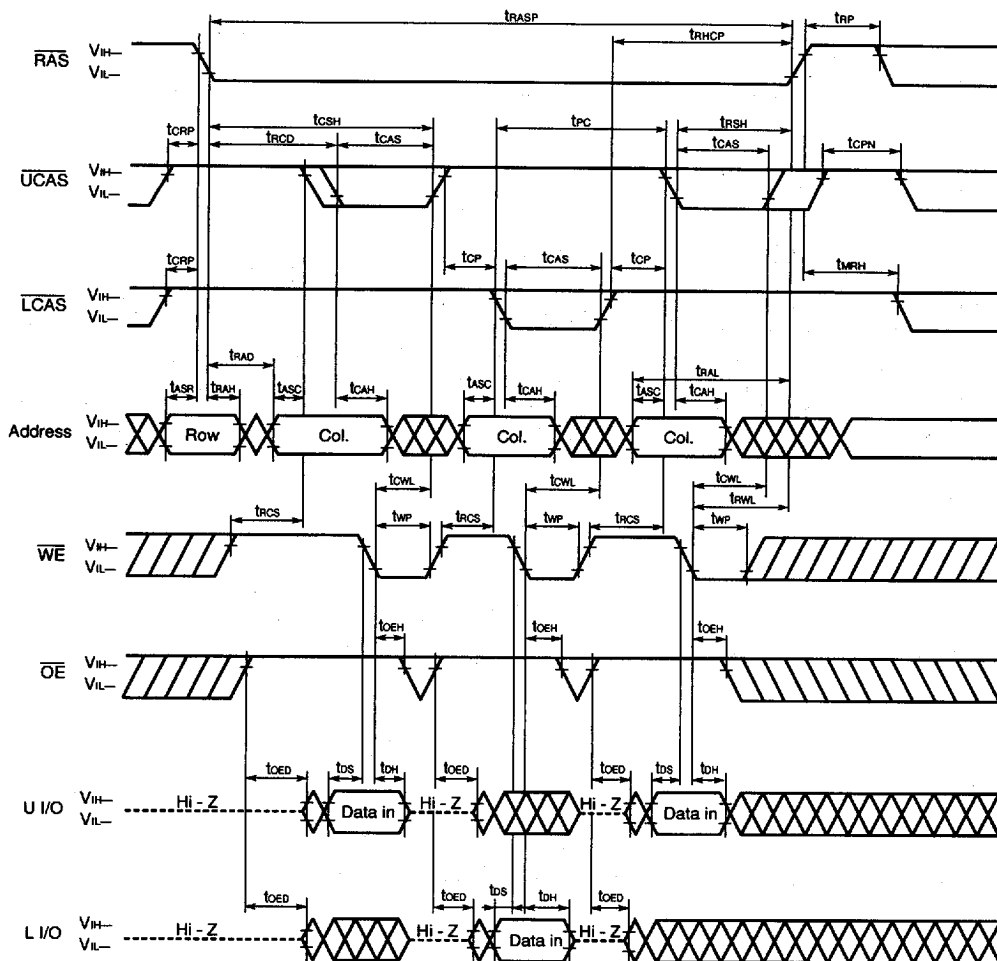
Remarks 1. $\overline{OE}$: Don't care

2. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.
3. This cycle can be used to control either UCAS or LCAS only. Or, it can be used to control UCAS or LCAS simultaneously, or at random.

[illegible]

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Fast Page Mode Byte Late Write Cycle

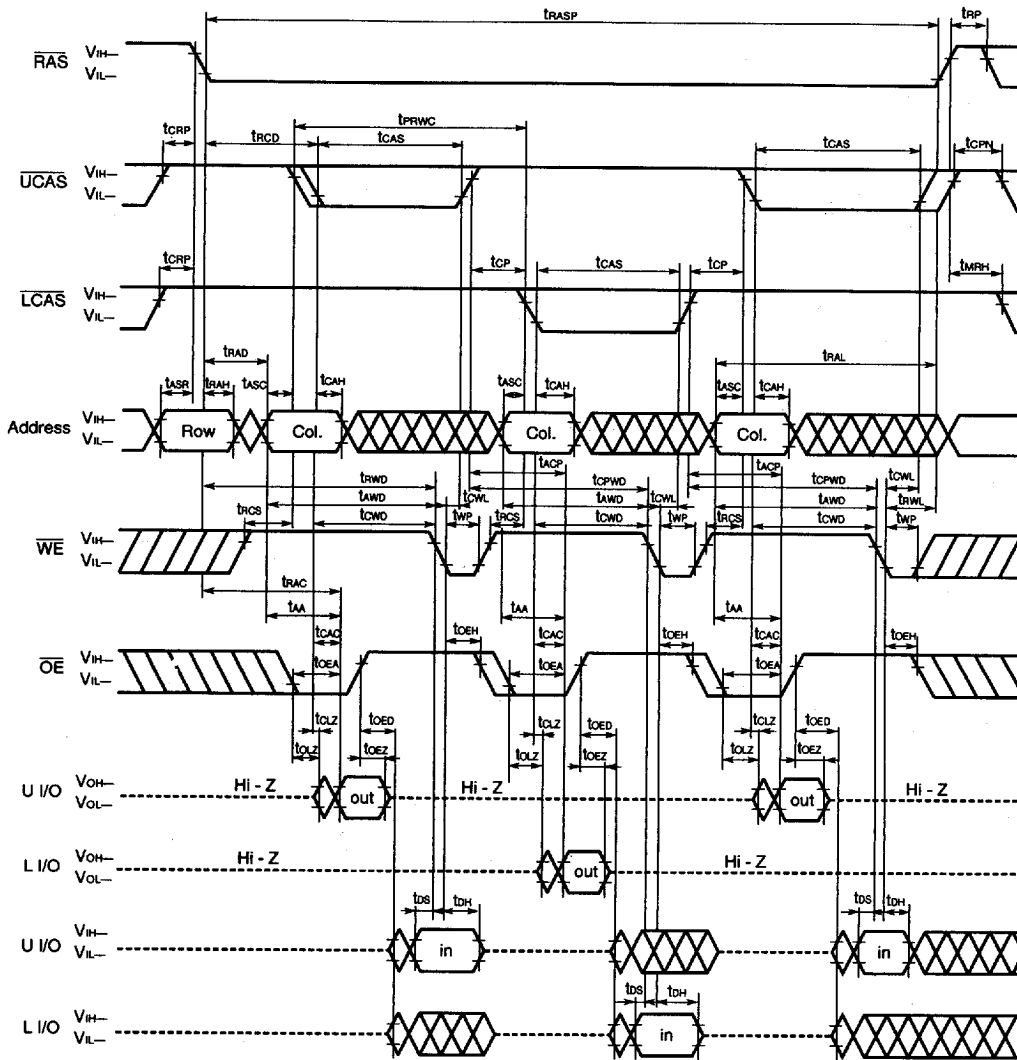


- Remarks**
1. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive CAS cycles within the same RAS cycle.
 2. This cycle can be used to control either $\overline{UCAS}$ or $\overline{LCAS}$ only. Or, it can be used to control $\overline{UCAS}$ or $\overline{LCAS}$ simultaneously, or at random.

The diagram illustrates the timing relationships for the 68000 microprocessor. It shows the signals RAS, UCAS, LCAS, Address, WE, OE, and U/I/O, along with their respective timing parameters. The signals are shown as waveforms, and the timing parameters are indicated by arrows and labels. The diagram is divided into four sections, each showing a different state of the microprocessor: Row, Col., Col., and Col. The signals are labeled with their high (V_{IH}) and low (V_{IL}) levels. The timing parameters are labeled with their respective symbols, such as t_{RASP}, t_{CRP}, t_{RCD}, t_{PRWC}, t_{CAS}, t_{CP}, t_{CPN}, t_{ASR}, t_{RAH}, t_{ASC}, t_{CAH}, t_{ACP}, t_{RWD}, t_{AWD}, t_{CWD}, t_{RCS}, t_{RAC}, t_{AA}, t_{OEH}, t_{OEA}, t_{OLZ}, t_{OED}, t_{OEZ}, t_{OS}, and t_{OH}.

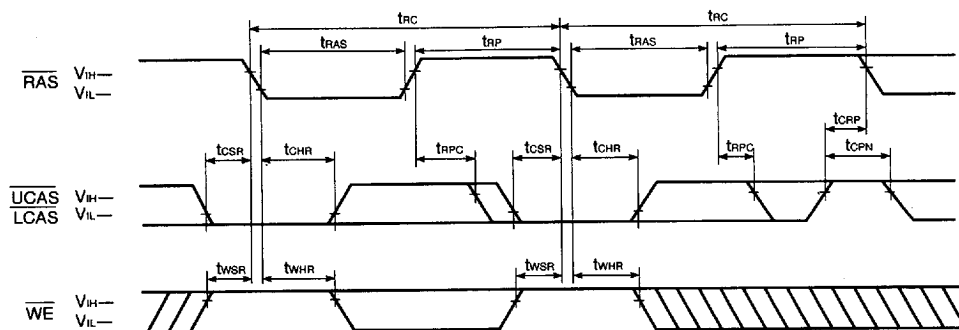
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Fast Page Mode Byte Read Modify Write Cycle



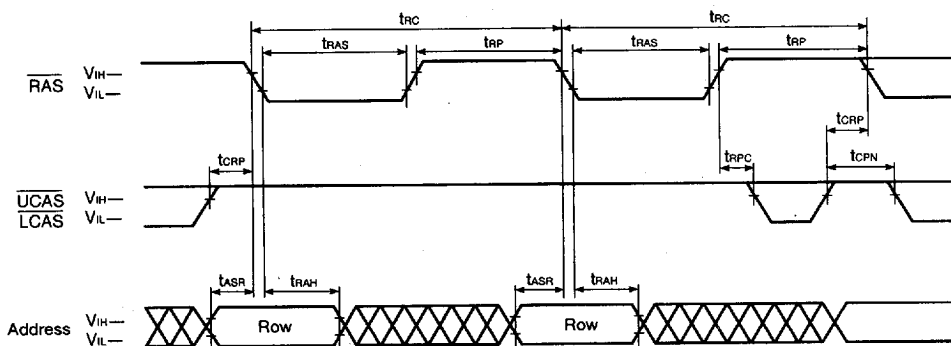
- Remarks**
1. In the fast page mode, read, write and read modify write cycles are available for each of the consecutive $\overline{\text{CAS}}$ cycles within the same $\overline{\text{RAS}}$ cycle.
 2. This cycle can be used to control either $\overline{\text{UCAS}}$ or $\overline{\text{LCAS}}$ only. Or, it can be used to control $\overline{\text{UCAS}}$ or $\overline{\text{LCAS}}$ simultaneously, or at random.

CAS Before RAS Refresh Cycle



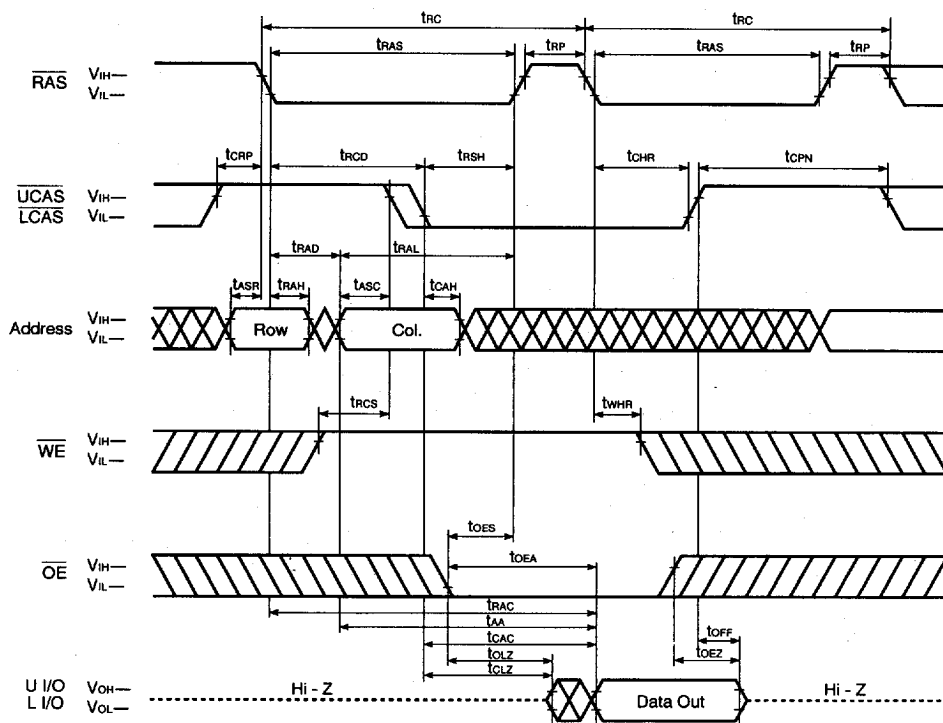
Remark Address, $\overline{OE}$: Don't care L I/O, U I/O: Hi-Z

RAS Only Refresh Cycle



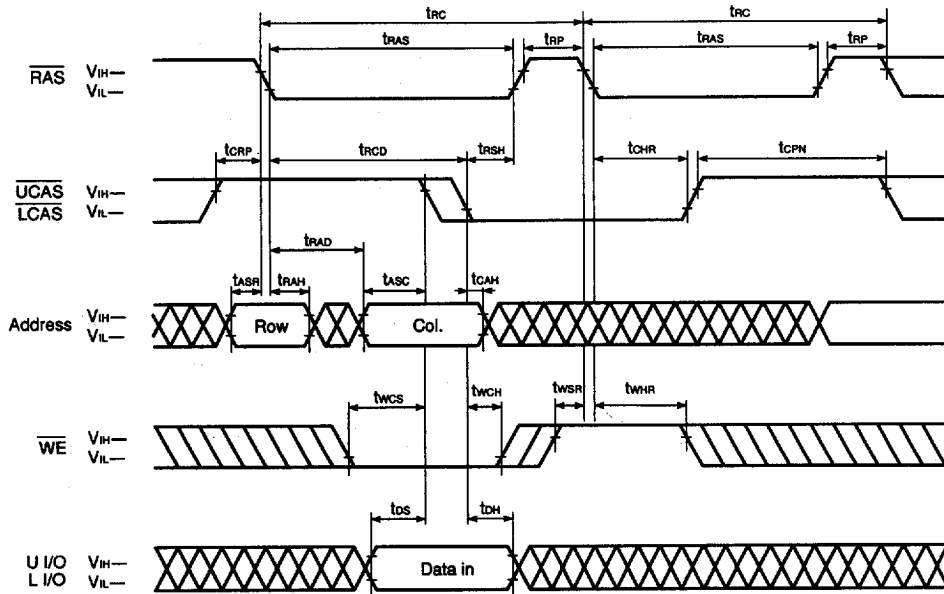
Remark $\overline{WE}$, $\overline{OE}$: Don't care L I/O, U I/O: Hi-Z

Hidden Refresh Cycle (Read)



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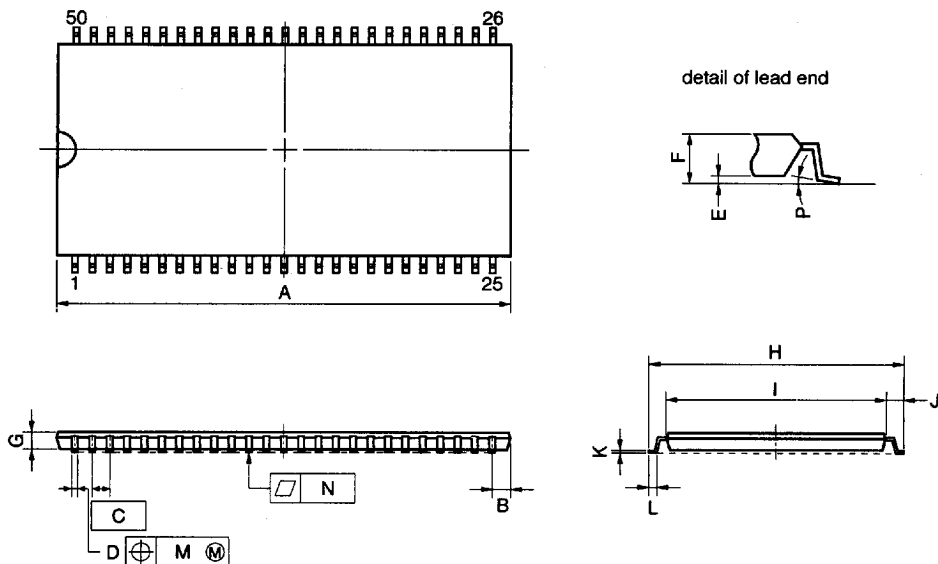
Hidden Refresh Cycle (Write)



Remark $\overline{\text{OE}}$: Don't care

Package Drawing

50PIN PLASTIC TSOP(II) (400 mil)



NOTE

Each lead centerline is located within 0.13 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	21.17 MAX.	0.834 MAX.
B	1.0 MAX.	0.040 MAX.
C	0.8 (T.P.)	0.031 (T.P.)
D	0.32 ^{+0.08} _{-0.07}	0.013±0.003
E	0.1±0.05	0.004±0.002
F	1.2 MAX.	0.048 MAX.
G	0.97	0.038
H	11.76±0.2	0.463±0.008
I	10.16±0.1	0.400±0.004
J	0.8±0.2	0.031 ^{+0.009} _{-0.008}
K	0.145 ^{+0.025} _{-0.015}	0.006±0.001
L	0.5±0.1	0.020 ^{+0.004} _{-0.005}
M	0.13	0.005
N	0.10	0.004
P	3° ^{+7°} _{-3°}	3° ^{+7°} _{-3°}

S50G5-80-7JF3

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